Se	arch Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/528,070	AOYAMA ET AL.
Examiner	Art Unit

James D. Ewart

2617

	SEAR	CHED	
Class	Subclass	Date	Examiner
455	25 63.1 63.4 67.11 272 423 446	1/12/2007	JDE
	561 562.1		
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343	700 757 878		
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342	350 357.1		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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Search Notes



10/528,070 Examiner

James D. Ewart

Applicant(s)/Patent under Reexamination

AOYAMA ET AL.

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455	25 63.1 63.4 67.11 272 423 446	1/12/2007	JDE
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INTERFERENCE SEARCHED		
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